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## A GOODNESS-OF-FIT TEST FOR A CLASS OF NONHOMOGENEOUS POISSON PROCESSES

#### 1. INTRODUCTION

The problem addressed here is that of testing the goodnessof-fit of certain integer valued stochastic processes. The hypothesis to be tested is that a set of waiting times are from a nonhomogeneous Poisson process which is a member of the class of processes with mean value function of the form

 $M(t) = \lambda t^{\beta} \quad t > 0. \tag{1.1}$ 

The occurrences of failures in military systems undergoing refinement in a test-fix-test-fix development process and in complex systems which are repaired upon failure are known to follow such processes. Crow (1) has discussed this application and shown how to use the Cramér-von Mises statistic to test the goodness-of-fit hypothesis. A table of the small sample distribution of the Cramér-von Mises statistic for the case in which an exponentially-appearing parameter is estimated also appeared in (1). Some percentiles of that table are inaccurate because of sample sizes used in the simulations which generated them. The objectives of the present work are to provide a more accurate table and to verify convergence to the asymptotic distribution. In addition various proofs were omitted from the previous work. Some of those proofs are included here for completeness.

The procedures presented here can also be used to test the hypothesis that a random sample from a continuous distribution has a cumulative distribution function  $F(X;\theta)$  of the form

 $F(X;\theta) = (R(X))^{\theta}$ (1.2)

for some positive value of the parameter  $\theta$  and for a specified cumulative distribution function R(X). Tables of the small sample distribution of the Cramér-von Mises test are provided to implement the test.

#### 2. THE CRAMER-VON MISES TEST IN THE PARAMETRIC CASE

Cramér (2), von Mises (3), and Smirnov (4) developed a test of the hypothesis that a random sample  $X_1, X_2, \ldots, X_N$  from a continuous distribution G(X) is drawn from the completely specified distribution function F(X). If the cumulative distribution function F(X) contains a parameter  $\Theta$ , then the hypothesis to be tested is that G(X) = F(X; $\Theta$ for some specified  $\Theta_0$ . The statistic employed in the test is given by

$$W_{n}^{2} = n \int_{-\infty}^{\infty} \left[F_{n}(X) - F(X;\theta_{o})\right]^{2} dF(X;\theta_{o}), \qquad (2.1)$$

where  $F_n(X)$  is the empirical distribution function. The empirical distribution function is defined as  $F_n(X) = k/n$  if k of the  $X_i$  are less than X. It can be shown that the statistic above can be written as

$$W_{n}^{2} = \frac{1}{12n} + \sum_{j=1}^{n} \left[ F(X_{j}^{\prime}; \theta_{0}) - \frac{2j-1}{2n} \right]^{2}$$
(2.2)

where  $X_j$  is the j-th order statistic of the random sample. The hypothesis that  $G(X) = F(X; \theta_0)$  is rejected if  $W_n^2$  is extraordinarily large. Smirnov derived the limiting distribution for  $W_n^2$  as the sample size n becomes large. Anderson and Darling (5) tabulated this distribution.

Following a suggestion of Cramér, Darling (6) extended this test to the case in which the parameter  $\theta$  is estimated by a statistic  $\hat{\theta}_n$  calculated from the data. This test assumes that there exists a nondegenerate interval I on the real axis such that for every  $\theta$  contained in the interior of I, F(X; $\theta$ ) is a cumulative distribution function. The hypothesis tested is that the cdf from which the sample is drawn is a member of the parametric family F(X; $\theta$ ) for some unknown value  $\theta_0$  in I.

For the parametric case the test statistic is

$$C_{n}^{2} = \frac{1}{12n} + \sum_{j=1}^{n} \left[ F(X_{j}; \hat{\theta}_{n}) - \frac{2j-1}{2n} \right]^{2}, \qquad (2.3)$$

in which the estimate  $\theta_n$  is substituted for the unknown parameter. Darling (6) investigated the limiting distribution of  $C_n^2$  and found that there are essentially two distinct cases. The first case is that of a superefficient estimator  $\hat{\theta}$ , such that

$$\lim_{n \to \infty} nE\left\{ \left( \hat{\theta}_n - \theta \right)^2 \right\} = 0, \qquad (2.4)$$

where  $\Theta$  is the true value of the unknown parameter. In this case the asymptotic distribution of  $C_n^2$  is the same as that of  $W_n^2$ . In the second and more general case the limiting distribution of  $C_n^2$  is different from that of  $W_n^2$ . Thus it is inappropriate to use the tabled critical

values for  $W_n^2$  to test the goodness-of-fit hypothesis in this case. If certain regularity conditions are satisfied and  $\sqrt{n}$  ( $\hat{\theta}_n - \theta$ ) is asympotically normal with mean zero and finite nonzero variance, then the limiting distribution of  $C_n^2$  is the same as that of  $\int_0^1 Y^2(t) dt$ where Y(t) is a Gaussian stochastic process with zero mean and a covariance kernel which depends upon the unknown true distribution G(X). Thus the  $C_n^2$  test is not distribution free; however, in important special cases the distribution depends only upon the form of the family f(X,  $\theta$ ) and not upon the true value  $\theta_0$ . Fortunately, for the case of an exponential parameter which is of concern in this report, the test has this property of being parameter free.

#### 3. NONHOMOGENOUS POISSON PROCESSES

Parzen (7) defines the concept of a nonhomogeneous Poisson process. This is an integer valued process which has independent increments and unit jumps and which consists of the random variables N(t), the number of events occurring in the interval [0,t]. It follows from this definition that for any t>0, the random variable N(t) has the Poisson distribution with an expected value given by some function M(t). The mean value function M(t) is nondecreasing and is usually assumed to be continuous and differentiable. The derivation of the mean value function is denoted by

 $v(t) = \frac{d}{dt} M(t)$  (3.1)

and is called the intensity function of the process. For a small increment of time h the quantity v(t) h is approximately equal to the probability of the occurrence of an event in the interval (t,t+h).

In the special case for which the mean value function is directly proportional to the observation time t, that is,

 $M(t) = \lambda t \tag{3.2}$ 

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the process is the ordinary homogeneous Poisson process. Such a process has a constant intensity function.

In the general case of the nonhomogeneous Poisson process . use of the characteristic function along with the property of independent increments reveals that for any interval (a,b) the number of events occurring in the interval has a Poisson distribution. The characteristic function of N(t) is

$$\phi_{N(t)}(u) = \exp[M(t) \{e^{iu} - 1\}] \qquad (3.3)$$

Since the numbers of events occurring in nonoverlapping intervals are independent we have

$$\phi_{N(b)-N(a)}^{(u)} = \frac{\phi_{N(b)}^{(u)}}{\phi_{N(a)}^{(u)}} = \exp \left\{ [M(b)-M(a)][e^{iu}-1] \right\} . \quad (3.4)$$

Thus the random variable N(b)-N(a) has the Poisson distribution with expected value M(b)-M(a).

A pair of well known theorems describe the relationship between the order statistics of a random sample from a uniform distribution and the waiting times to the occurrence of events in a homogeneous Poisson process. The proof of the first is given by Parzen. The statements of both theorems and the proofs are presented here to clarify this relationship.

Theorem 1. Let { N(t), t>0 } be a Poisson process with constant intensity  $\lambda$ . Under the condition that N(T)=n, the times  $t_1, t_2, \ldots, t_n$  in the interval (0,T] at which events occur have the joint probability density function

$$f(t_1, t_2, \cdots, t_n | N(T)=n) = \frac{n!}{T^n}$$
 (3.5)

in which  $0 < t_1 < t_2 < \cdots < t_n \leq T$ . Note that this joint conditional density is the same as that of the order statistics of a random sample size n drawn from a uniform distribution defined on the interval (0,T].

Proof: The probability that exactly n events occur in the interval (0,T] is

$$P[N(T)=n] = \frac{(\lambda T)^n e^{-\lambda T}}{n!}$$
 (3.6)

Let  $\{t_i\}$  be a set of times such that  $o \neq_1 < t_2 < \cdots < t_n < T$  and choose a set of increments  $\{h_1, h_2, \cdots, h_n\}$  such that the intervals  $[t_1, t_1 + h_1]$ ,  $[t_2, t_2 + h_2], \cdots [t_n, t_n + h_n]$  are nonoverlapping. Since the increments are nonoverlapping the number of occurrences in each interval and the number occuring elsewhere in (0,T] are independent. Thus the probability that exactly one event occurs in each interval  $[t_i, t_i + h_i]$  for i=1,2...,nand no events occur elsewhere in (0,T] is

$$\exp\left[-\lambda\left(T-\prod_{i=1}^{n}h_{i}\right)\right]\prod_{j=1}^{n}\lambda h_{j}e^{-\lambda hj}$$
(3.7)

The conditional probability of this event given that N(t) = n is

$$\frac{n!}{T^{n}} \prod_{i=1}^{n} h_{i} \qquad (3.8)$$

By allowing the  $h_i$  to decrease to infinitesimal increments, it follows that the conditional density of  $t_1, t_2, \ldots, t_n$  given that N(t)=N is as stated in the theorem.

<u>Theorem 2</u>. Let  $\{N(t), t \ge 0\}$  be a Poisson process with constant intensity  $\overline{\lambda}$ . Let  $t_n$  be the time of occurrence of the nth event. Under the condition that  $t_n = T$ , the n-1 waiting times  $t_1, t_2, \ldots, t_{n-1}$  have the joint probability density function

$$f(t_1, t_2, \dots, t_{n-1} | t_n = T) = \frac{(n-1)!}{T^{n-1}}$$
 (3.9)

Note that this point conditional density is the same as that of the order statistics of a random sample of size n-1 drawn from a uniform distribution defined on the interval (0,T].

Proof: Define  $t_0=0$  and let  $s_i=t_i-t_{i-1}$  be the i-th interarrival time of the Poisson process. It is known that the interarrival times are independently identically distributed random variables with the exponential distribution with mean  $1/\lambda$ . Thus the joint density of the first n interarrival times is

$$f(s_1, s_2, \dots, s_n) = \prod_{i=1}^n \lambda e^{-\lambda s_i} = \lambda^n \exp[-\lambda \sum_{i=1}^n s_i]$$
(3.10)

for which  $0 < s_1, s_2, \ldots, s_{n-1}, < \bullet$ . The transformation mapping  $(t_1, t_2, \ldots, t_{n-1})$  into  $(s_1, s_2, \ldots, s_{n-1})$  has a Jacobian identically equal to unity. Therefore the joint density of the waiting times is

$$g(t_1, t_2, \dots, t_n) = \lambda^n e^{-\lambda t_n}$$
(3.11)

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## with $0 < t_1 < t_2, \dots < t_n$ .

Since t is the convolution of n random variables from the same exponential distribution, it has the gamma density

$$g_n(t_n) = \frac{\lambda e^{-\lambda t_n (\lambda t_n)^{n-1}}}{(n-1)!} t > 0$$
 (3.12)

It follows that the conditional density of  $t_1, \ldots, t_{n-1}$  given that  $t_n = T$  is as in the statement of the theorem.

A nonhomogeneous process with a continuous mean value function M(t) can be transformed into a homogeneous Poisson process. Because M(t) is continuous and nondecreasing its inverse function  $M^{-1}(X)$  can be defined for all X>0 as the minimum value of t such that M(t)>X. Define the stochastic process  $\{K(X), X>0\}$ 

$$K(X) = N(M^{-1}(X))$$
 (3.13)

This is a Poisson process with an intensity function identically equal to one. This transformation will be used in the proof of the two subsequent theorems.

<u>Theorem 3.</u> Let  $\{N(t), t\geq 0\}$  be a Poisson process with continuous mean value function M(t). Under the condition that N(T) = n, the n waiting times  $t_1, t_2, \ldots, t_n$  in the interval (0,T] at which events occur are random variables having the same distribution as the order statistics of a random sample of size n from the probability density

$$h(X) = \frac{v(X)}{M(T)} \quad 0 \le X \le T$$
 (3.14)

where v(X) = dM(X)/dx is the intensity function of the Poisson process. That is,

$$g(t_1, t_2, \dots, t_n | N(T) = n) = \frac{n!}{[M(T)]^n} \prod_{i=1}^n v(t_i)$$
 (3.15)

with  $0 < t_1, < t_2 < \ldots < t_n < T$ .

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Proof: Define the inverse of the mean value function and the stochastic process  $\{K(X), x \ge 0\}$  as in the preceding paragraph. It follows that the quantities  $M(t_i) = X_i$  for i = 1, 2, ..., N are the first N waiting times from a Poisson process with intensity identically equal to unity and occurring in the interval (0, M(T)]. By theorem 1 the joint conditional density of  $X_1, ..., X_N$  given that N[M(T)] = n is

$$\mathbf{f}(X_{1}, X_{2}, \dots, X_{n} \mid N(M(T)) = n) = \frac{n!}{[1(T)]^{n}} \stackrel{0 \leq X_{1} \leq X_{2} \leq \dots \leq X_{n} \leq !(T)}{(3.16)}$$

The absolute value of the Jacobian of the transformation which maps  $(t_1, t_2, \ldots, t_n)$  into  $(X_1, X_2, \ldots, X_n)$  is given by

 $\begin{array}{c} n & \partial X_{i} \\ \pi & \underline{-1}_{i} \\ i=1 & \partial t_{i} \end{array} , which is$ 

 $\left|J\right| = \prod_{i=1}^{n} v(t_i) \qquad (5.17)$ 

It follows that the conditional density  $g(t_1, t_2, \ldots, t_n | N(t)=n)$  is as given in the theorem. Note that the distribution function corresponding to the density h(X) is given by

$$H(X) = \frac{M(X)}{M(T)} \qquad 0 \le X \le T$$
 (3.18)

<u>Theorem 4.</u> Let {N(t),t>0} be a Poisson process with continuous mean value function M(t). Under the condition that the waiting time to the nth event,  $t_n$ , is equal to T, the n-1 waiting times  $t_1 < t_2 < \ldots < t_{n-1}$  in the interval (0,T) at which events occur are random variables having the same distribution as the order statistics of a random sample of size n-1 from the probability density

$$h(X) = \frac{v(X)}{M(T)} = \frac{0 < X < T}{0 < X < T}$$
 (3.19)

where  $v(X) = \frac{dM(x)}{dx}$  is the intensity function of the Poisson process. That is.

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$$g(t_1, t_2, \dots, t_{n-1} | t_n = T) = \frac{(n-1)!}{[M(T)]^{n-1}} \prod_{i=1}^{n-1} v(t_i)$$
 (3.20)

with  $0 \le t_1 \le t_2 \le \ldots \le t_{n-1} \le T$ .

Proof: The proof is the same as that of theorem 3 except that theorem 2 is applied instant of theorem 1 and the Jacobian is given by

$$\left|J\right| = \prod_{i=1}^{n-1} v(t_i) \qquad (3.21)$$

Theorems 3 and 4 provide the basis for testing hypotheses concerning the mean value function of a Poisson process. Define the parameter m as follows

$$m = \begin{cases} n & \text{for the condition } N(T) = n \\ n-1 & \text{for the condition } t_n = T \end{cases}$$
(3.22)

in which n is the number of events observed in the interval (0,T] of a stochastic process  $\{N(t), t \ge 0\}$ . Consider the hypothesis  $H_0: N(t)$  is a Poisson process with continuous mean value function M(t). If  $H_0$  is true the waiting times  $t_1, t_2, \ldots, t_m$  have the same distribution as the order statistics of a random sample of size m from the distribution H(X) = M(X)/M(T). Define  $H_m(X)$  to be N(X)/N(T). Then the statistic

 $W_{m}^{2} = m f_{0}^{T} [H_{m}(X) - H(X)]^{2} dH(X)$  (3.23)

has the same distribution as the Cramér-von Mises statistic for a sample of size m from H(X). The statistic can be written in the form

$$W_{\rm m}^2 = \frac{1}{12m} + \sum_{j=1}^{\rm m} \left[\frac{M(t_j)}{M(T)} - \frac{2_{j-1}}{2m}\right]^2 , \qquad (3.24)$$

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which is more suitable for computation.

If the mean value function contains an unknown parameter  $\theta$ , then it is desirable to estimate the parameter from the data by calculating a statistic  $\hat{\theta}_m$ . If the estimator  $\hat{\theta}_m$  satisfies the properties listed by Darling, then the statistic

$$C_{m}^{2} = \frac{1}{12m} + \sum_{j=1}^{m} \left[ \frac{M(t_{j}; \hat{\theta})}{M(T, \hat{\theta}_{m})} - \frac{2_{j}-1}{2m} \right]^{2}$$
(3.25)

may be used to test the hypothesis  $H_1$ : {N(t)t>0} is a Poisson process with mean value function M(T; $\theta$ ) for some  $\theta$ . The test is truly usable if the statistic  $C_m^2$  is parameter-free.

## 4. THE RELIABILITY GROWTH PROCESS

Crow (8) has shown that the improvement in reliability of a complex system undergoing development in a test-fix-test-fix environment can be modeled by a certain family of nonhomogeneous Poisson processes. Crow (1) uses this same family of processes to represent the occurrences of failures in complex repairable systems. For this class of processes the mean value function is of the form

$$M(t) = \lambda t^{P} \qquad \lambda > 0; \beta > 0; t > 0 \qquad (4.1)$$

in which  $\lambda>0$  can be interpreted as a scale parameter and  $\beta>0$  as a shape parameter. The corresponding intensity function is

$$v(t) = \lambda \beta t^{B-1}$$
 t>0. (4.2)

This family includes the homogeneous Poisson processes as the special case in which  $\beta$  equals unity.

The results of the preceding section can be used to derive a goodness of fit test for this class of processes. With the index m defined as in Section 3, it follows from theorems 3 and 4 that with

application of the appropriate condition the random variables  $t_1, t_2, \ldots, t_m$  have the same distribution as the order statistics of a random sample for the cumulative distribution function

$$H(X) = \left(\frac{X}{T}\right)^{\beta} \qquad 0 \le X \le T \quad . \tag{4.3}$$

With the appropriate choice of a estimator  $\beta$  the statistic

$$C_{m}^{2} = \frac{1}{12m} + \sum_{j=1}^{m} \left[ \frac{t_{j}}{T} \right]^{\overline{\beta}} - \frac{2_{j}-1}{2m} \right]^{2}$$
(4.4)

can be used to test the hypothesis that the observations  $\{t_j\}$  are from Poisson process with mean value function of the form  $M(t) = \lambda t^{\beta}$ . Darling has shown that the distribution of this test statistic is independent of the true value of the parameter  $\beta$ . In fact it is distribution free over the class of distributions such that

$$F(X;\beta) = \left[ R(X) \right]^{\beta} \qquad \beta > 0 \qquad (4.5)$$

for some cumulative distribution function R(X).

As Crow has shown conditional maximum likelihood estimates of  $\beta$  can be derived from equation (3.15) for the case N(T) = n and from equation (3.20) for the case t = T. These conditional maximum likelihood estimates are given by

$$\hat{\beta} = \frac{m}{\min T - \sum_{i=1}^{m} \ln t_i}$$
(4.6)

in which m = n for conditioning on N(T) = n and m = n-1 for conditioning

on  $t_n = T$ . This is a biased estimator for  $\beta$  with expected value

$$E(\tilde{\beta}) = \frac{m}{m-1} \beta \qquad (4.7)$$

An unbiased estimate can thus be provided by

$$\overline{\beta} = \frac{m-1}{\min T - \sum_{i=1}^{m} \ln t_i}$$
(4.8)

It can be shown that the estimator  $\overline{\beta}$  given in equation (4.8) should be used in equation (4.4) to calculate the statistic  $C_m^2$ . This must be done in order to satisfy the conditions needed for  $C_m^2$  to have the limiting distribution described by Darling. In particular, the condition

$$\lim_{m \to \infty} \mathrm{mE}(\overline{\beta} - \beta) = 0 \tag{4.9}$$

is satisfied since  $\overline{\beta}$  is unbiased. This condition is not met by the estimator in equation (4.6).

5. DISTRIBUTION OF THE STATISTIC  $C_m^2$ 

In order to use the statistic  $C_m^2$  to test the goodness of fit hypothesis it is necessary to establish a table of critical values for selected significance levels. The small sample distribution of the statistic  $C_m^2$  given in equation (4.4) is not analytically tractable. Moreover, the limiting distribution has only been defined in terms of its characteristic function. The distribution of  $C_m^2$  has been determined through Monte Carlo simulation for values of m from 2 to 20 and for m equal to 30, 60, and 100.

The Monte Carlo simulation consists of repeated samples of

size m from the uniform distribution on the interval (0,1) and computation of

$$\overline{\beta} = \frac{m-1}{\underset{j=1}{\overset{m}{\longrightarrow}} 1n \ U_{j}}$$
(5.1)

and

$$C_{m}^{2} = \frac{1}{12m} + \sum_{j=1}^{m} \left[ \left( u_{j}^{\prime} \right)^{\overline{\beta}} - \frac{2j-1}{2m} \right]^{2}$$
 (5.2)

in which  $\{u_j\}$  is the random sample and  $\{u_j'\}$  is the corresponding set of order statistics. For each value of the index m there are 150,000 replications of this sampling.

Selected percentage points of the distribution of  $C_m^2$  are presented in Table 1. The 1- $\alpha$  percentile of this distribution is to be used for a goodness of fit test with level of significance  $\alpha$ . The accuracy of these percentage points can be determined by using the fact that any percentile of a random sample is asymptotically normal. Each sample of 150,000 actually consists of ten independent samples of size 15,000. The sample variance of estimate  $\hat{C}_p$ . of the p-th percentile is used to estimate the precision of the p-th percentile of the combined sample. Table 2 contains interval estimates of the percentiles of the distribution of  $C_m^2$  with a confidence coefficient of .90.

The sample moments from the simulation can be used to determine how rapidly the distribution of  $C_m^2$  is converging to the limiting distribution. Darling provided a means for calculating the moments of the limiting distribution. The mean, variance, and third central moment,  $\mu_3$ , of the sampling distribution of  $C_m^2$  and of the limit distribution are given in Table 3. The sample moments indicate the distribution for m equal to 100 matches the limiting distribution quite closely. The mean, variance, and third central moment from the simulation for m equal to 100 are each within one percent of the respective true moment of the limiting distribution. Hence the percentiles appearing in Table 1 for m equal to 100 can be used for larger values of m. Figure 1 contains plots of the empirically obtained density function for m equal to 5 and m equal to 100.

#### 6. CONCLUSION

The percentiles in Table 1 provide a set of critical values for the Cramér-von Mises goodness of fit statistic for the case in which an exponential parameter is estimated. This table can be used to test the hypothesis that a random sample of size m comes from a parametric family in the class of distribution of the form

$$F(X;\theta) = \left(R(X)\right)^{\theta} \quad \theta > 0 \quad (6.1)$$

in which R(X) is some cumulative distribution function. The parameter  $\theta$  is to be estimated from the data by an appropriate statistic.

The distribution of the Cramér-von Mises statistic can also be used to test hypotheses on the goodness of fit for certain stochastic processes. In particular, the hypothesis that a stochastic process is a member of the family of nonhomogeneous Poisson processes with mean value function of the form

$$M(t) = \lambda t^{\beta}$$
 (6.2)

can be tested through use of the statistic.

| P  | . 80 | . 85 | .90  | .95  | .99  |
|----|------|------|------|------|------|
| 1  |      | 000  |      |      |      |
| 2  | .138 | .149 | .162 | .175 | .186 |
| 5  | .121 | .135 | .154 | .184 | .23  |
| •  | .121 | .134 | .155 | .191 | .28  |
| 5  | .121 | .137 | .160 | .199 | . 30 |
| 5  | .123 | .139 | .162 | .204 | . 31 |
| 7  | .124 | .140 | .165 | .208 | . 32 |
| 3  | .124 | .141 | .165 | .210 | . 32 |
| )  | .125 | .142 | .167 | .212 | . 32 |
| 0  | .125 | .142 | .167 | .212 | . 32 |
| 1  | .126 | .143 | .169 | .214 | . 32 |
| 2  | .126 | .144 | .169 | .214 | . 32 |
| 13 | .126 | .144 | .169 | .214 | .33  |
| 4  | .126 | .144 | .169 | .214 | . 33 |
| 15 | .126 | .144 | .169 | .215 | .33  |
| 16 | .127 | .145 | .171 | .216 | . 33 |
| 17 | .127 | .145 | .171 | .217 | .33  |
| 18 | .127 | .146 | .171 | .217 | .33  |
| 19 | .127 | .146 | .171 | .217 | .33  |
| 20 | .128 | .146 | .172 | .217 | .33  |
| 30 | .128 | .146 | .172 | .218 | . 33 |
| 0  | .128 | .147 | .173 | .220 | .33  |
| 00 | .129 | .147 | .173 | .220 | . 34 |

|             |     | TAB | LE 1         |    |         |  |
|-------------|-----|-----|--------------|----|---------|--|
| PERCENTILES | FOR | THE | DISTRIBUTION | OF | $c_m^2$ |  |

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the second s

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es the

| P   | . 80      | .85       | .90       | .95         | .99           |
|-----|-----------|-----------|-----------|-------------|---------------|
| M   |           |           |           |             |               |
| 2   | .13721378 | .14851493 | .16131618 | .17481753   | .18631866     |
| 3   | .12031212 | .13461356 | .15411548 | .18281843   | .22932320     |
| 4   | .12041211 | .13371346 | .15391552 | .19011924   | .27612819     |
| 5   | .12021212 | .13591372 | .15881605 | .19842006   | .29232978     |
| 6   | .12201232 | .13841395 | .16091633 | .20182054   | .30293115     |
| 7   | .12331242 | .13961406 | .16391652 | .20622096   | .31283202     |
| 8   | .12331245 | .14001414 | .16441663 | .20842106   | .31433238     |
| 9   | .12451253 | .14191428 | .16671683 | .21092130   | .31913261     |
| 10  | .12431257 | .14161429 | .16631684 | .21082136   | . 3208 3264   |
| 11  | .12531263 | .14291439 | .16811691 | .21282160   | , 3249-, 3302 |
| 12  | .12601268 | .14311441 | .16791697 | .21242151   | .32153276     |
| 13  | .12631272 | .14401451 | .16951711 | .21402164   | . 3230 3312   |
| 14  | ,12591269 | .14351445 | .16861697 | .21302154   | .32613322     |
| 15  | .12561270 | .14331451 | .16801707 | .21382164   | .32573301     |
| 16  | .12661278 | .14401454 | .17011714 | .21462174   | ,32163291     |
| 17  | .12681281 | .14461455 | .16971713 | .21522181   | . 3288 3351   |
| 18  | .12711278 | .14501462 | .17021721 | .21512184   | . 3258 3344   |
| 19  | .12661281 | .14431462 | .16991721 | .21542184   | .32923359     |
| 20  | .12711280 | .14511461 | .17061725 | .21622188   | .32963358     |
| 30  | .12751286 | .14511470 | .17151733 | .21722197   | .32873355     |
| 60  | .12761290 | .14591475 | .17271742 | . 2200 2219 | .33103357     |
| 100 | .12841297 | .14621479 | .17201742 | .21822212   | .33323392     |

INTERVAL ESTIMATES OF PERCENTILES OF THE DISTRIBUTION C<sup>2</sup><sub>II</sub> 90% CONFIDENCE COEFFICIENT

TABLE 2

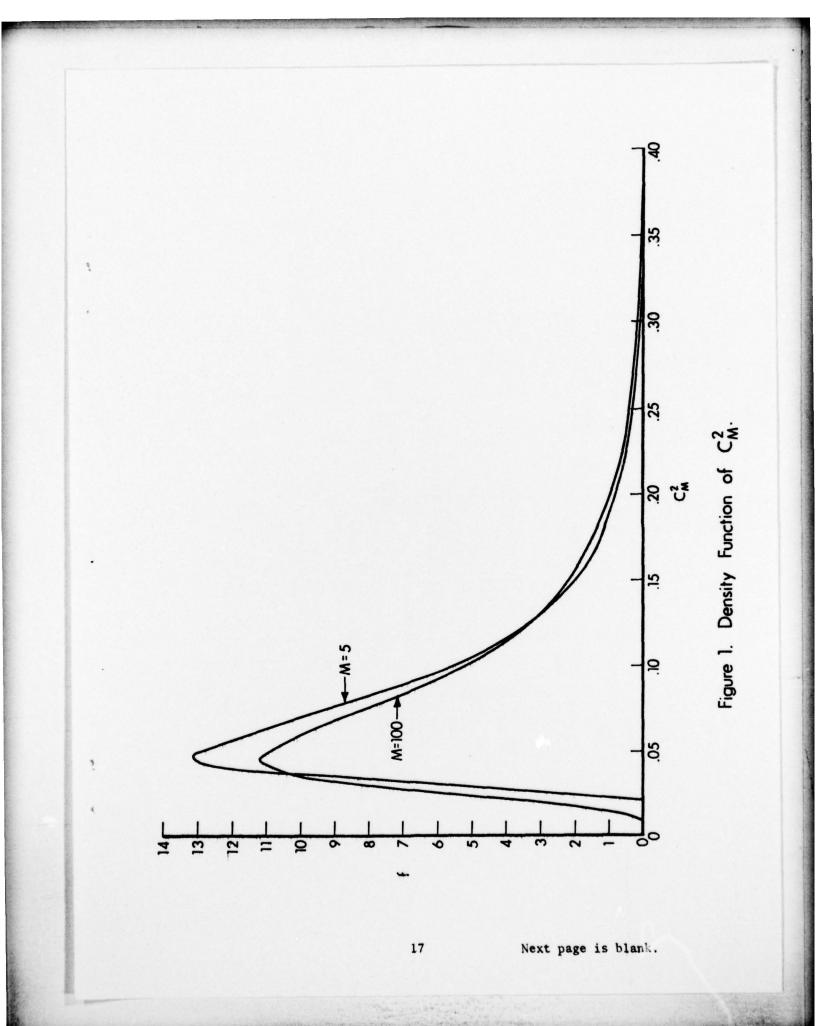
| М   | Mean  | Variance | μ       |
|-----|-------|----------|---------|
| 2   | .1124 | .00082   | .000026 |
| 3   | .0929 | .00179   | .000107 |
| 4   | .0898 | .00267   | .000281 |
| 5   | .0892 | .00319   | .000409 |
| 6   | .0894 | .00347   | .000471 |
| 7   | .0899 | .00375   | .000550 |
| 8   | .0897 | .00383   | .000565 |
| 9   | .0903 | .00393   | .000550 |
| 10  | .0902 | .00391   | .000546 |
| 11  | .0906 | .00405   | .000599 |
| 12  | .0506 | .00405   | .000602 |
| 13  | .0910 | .00410   | .000609 |
| 14  | .0908 | .00409   | .000603 |
| 15  | .0909 | .00411   | .000619 |
| 16  | .0911 | .00411   | .000599 |
| 17  | .0914 | .00418   | .000643 |
| 18  | .0915 | .00421   | .000639 |
| 19  | .0914 | .00418   | .000617 |
| 20  | .0914 | .00424   | .000625 |
| 30  | .0917 | .00425   | .000632 |
| 60  | .0920 | .00429   | .000629 |
| 100 | .0922 | .00432   | .000644 |
|     | .0926 | .00436   | .000640 |
|     |       |          |         |

| TABLE | 3 |  |
|-------|---|--|
|-------|---|--|

MOMENTS OF THE DISTRIBUTION OF C<sup>2</sup>

16

and a superstant of the design of the super-super states



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